Anubhav Diwan

List of Publications by Year
in descending order

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11	158	1307594 7	1372567 10
papers	citations	h-index	g-index

11	11	11	211
all docs	docs citations	times ranked	citing authors

#	Article	IF	Citations
1	Semiempirical Peak Fitting Guided by ab Initio Calculations of X-ray Photoelectron Spectroscopy Narrow Scans of Chemisorbed, Fluorinated Silanes. Langmuir, 2020, 36, 1878-1886.	3.5	10
2	Sputtered silicon solid phase microextraction fibers with a polydimethylsiloxane stationary phase with negligible carry-over and phase bleed. Journal of Chromatography A, 2020, 1623, 461065.	3.7	13
3	A perspective on two chemometrics tools: PCA and MCR, and introduction of a new one: Pattern recognition entropy (PRE), as applied to XPS and ToF-SIMS depth profiles of organic and inorganic materials. Applied Surface Science, 2018, 433, 994-1017.	6.1	36
4	Layerâ€byâ€layer deposition of nitrilotris(methylene)triphosphonic acid and Zr(IV): an XPS, ToFâ€SIMS, ellipsometry, and AFM study. Surface and Interface Analysis, 2016, 48, 105-110.	1.8	2
5	New Data Analysis Tools for X-ray Photoelectron Spectroscopy (XPS) and Spectroscopic Ellipsometry (SE): Uniqueness Plots and Width Functions in XPS, and Distance, Principal Component, and Cluster Analyses in SE. Microscopy and Microanalysis, 2016, 22, 344-345.	0.4	0
6	Uniqueness plots: A simple graphical tool for identifying poor peak fits in X-ray photoelectron spectroscopy. Applied Surface Science, 2016, 387, 155-162.	6.1	51
7	Porous, High Capacity Coatings for Solid Phase Microextraction by Sputtering. Analytical Chemistry, 2016, 88, 1593-1600.	6.5	22
8	Superhydrophobic Surfaces with Very Low Hysteresis Prepared by Aggregation of Silica Nanoparticles During <I>In Situ</I> Urea-Formaldehyde Polymerization. Journal of Nanoscience and Nanotechnology, 2015, 15, 10022-10036.	0.9	1
9	Fluorine plasma treatment of bare and nitrilotris(methylene)triphosphonic acid (NP) protected aluminum: an XPS and ToF-SIMS study. Surface and Interface Analysis, 2015, 47, 56-62.	1.8	9
10	Self-termination in the gas-phase layer-by-layer growth of an aza silane and water on planar silicon and nylon substrates. Journal of Vacuum Science and Technology B:Nanotechnology and Microelectronics, 2014, 32, 061803.	1.2	1
11	Spectroscopic ellipsometric modeling of a Biâ€“Teâ€“Se write layer of an optical data storage device as guided by atomic force microscopy, scanning electron microscopy, and X-ray diffraction. Thin Solid Films, 2014, 569, 124-130.	1.8	13